beneficial taper functions can be applied to these sparse double-arrays, where conventional taper functions would fail.

REFERENCES


On a Class of Planar Absorbers With Periodic Square Resistive Patches

Hosung Choo, Hao Ling, and Charles S. Liang

Abstract—A Pareto genetic algorithm is used to explore the performance of planar absorbers incorporating a sheet of periodic resistive patches embedded in a primary material substrate. The absorbing performance of a single-layer electric radar absorbing material (eRAM) with periodic resistive patches is compared to that of standard dual-layer absorbers made of wax laid on top of eRAM or magnetic radar absorbing material (m-RAM).

Index Terms—Pareto genetic algorithm, periodic resistive patches, planar absorbers.

I. INTRODUCTION

The practical application of radar absorbers on aerospace vehicles can broadly be categorized into radar absorbing structures (RAS) [1], [2] and radar absorbing materials (RAM). RAMs are primarily made of cellular core materials (loaded core or sandwiched loaded sheets) designed to handle partial structural load and are generally less than 100 dB.

Manuscript received July 10, 2006; revised January 9, 2008. Published July 7, 2008 (projected). This work was supported in part by the Office of Naval Research under Contract N00014-01-1-0224, in part by the Texas Higher Education Coordinating Board under the Texas Advanced Technology Program, and in part by the National Science Foundation Major Research Instrumentation Program.

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Digital Object Identifier 10.1109/TAP.2008.924766
50 mm thick for flat-panel usage. On the other hand, RAM are thin coatings of structurally parasitic absorbing materials generally less than 6.5 mm in thickness. They are preferred for use due to their lower volume, lighter weight, and minimal structural impact, provided the design can meet the required electrical performance. Thus far, multilayered RAM designs have been confined to academic interest due to difficulties in developing materials with suitable electrical and mechanical properties and lack of robust manufacturing techniques to assemble dissimilar materials. In general, dual-layer designs are considered only if broadband and wide angular electrical performances are essential.

Recently, Terracher and Berginc [3] proposed a method to simultaneously lower the operating frequency and broaden the bandwidth of a single-layer, non-magnetic eRAM absorber. Their design entails placing periodic, perfectly conducting (PEC), square patches on the top surface of a planar eRAM. Even though the lossy dielectric material used is a rather poor stand-alone absorber, the layer of periodic metallic patches dramatically improves the performance of the combination to a respectable level. The objective of this Communication is to explore whether their design can be further optimized and generalized such that the resultant performance can nearly match that of a dual-layer magnetic RAM (magRAM). If so, then the design may potentially be easier to implement in practice than the dual-layer magRAM.

The use of genetic algorithms (GAs) in the design of multilayered planar absorber structures has been extensively studied [4]–[7]. Corrugated coatings with periodic non-planar shape profiles offer additional degrees of design freedom, and GA-optimized non-planar coating structures have been also reported by the authors [8]. In this paper, the Pareto GA coupled with a full-wave electromagnetic solver is used to design low-profile planar periodic absorber for broadband and wide angular operations. First, the optimal set of designs on the Pareto front are found for the patch absorbers used in [3] by trading off coating thickness and absorbing characteristics. Then, the designs are further refined by exploring additional degrees of freedom including the patch resistivity, size, period, and its height within the substrate. Finally, the performances of the optimized designs are compared against results obtained from the standard dual-layered absorber designs. Several GA optimized designs with different thickness are shown, and the physical interpretations of the resultant performance are also discussed.

II. PARETO GA OPTIMIZATION

The geometry considered is shown in Fig. 1. The absorber consists of a single layer of lossy material backed by a perfectly conducting ground-plane. Planar square resistive patches are embedded periodically inside the lossy material. The incident wave direction is defined as $\theta$ measured from normal to the substrate. The design parameters are the coating thickness ($T$) and the patch size ($W$), resistivity ($R$), period ($P$), and height above ground-plane ($T_1$). A Pareto GA is implemented to search for the optimal design parameters for achieving two critical design objectives: low profile and good absorption performance. The two costs associated with the design goals are

$$
\text{Cost 1} = \text{Absorber coating thickness (} T \text{)}
$$

$$
\text{Cost 2} = \text{Average power reflection coefficient}
$$

$$
\frac{1}{2N} \sum_{j=0}^{N} \left( |\Gamma_\perp|^2 + |\Gamma_\parallel|^2 \right)
$$

where the $\Gamma$’s represent the field reflection coefficients for the perpendicular and parallel polarized incident waves within the frequency-angular range of interest. It is worthwhile pointing out that other cost definitions (such as minimax) for Cost2 can also be used. This issue was examined previously in [8]. The results did not show significant differences among the various cost definitions. The present designs are confined within the frequency band of $f = 6$ to 12 GHz and the angular region of $\theta = 30^\circ$ to $60^\circ$. After evaluating the cost functions of each sample structure using a full-wave periodic patch code [9], all the samples of the population are ranked using the non-dominated sorting method. Then, a reproduction process is performed to refine the population into the next generation based on their rank. In order to prevent solutions from converging to a single point, the sharing scheme described in [10] is used to generate a well-dispersed population. The final converged “Pareto front” contains those absorber designs that are optimal in at least one of the two objectives.

III. RESULTS

The Pareto GA process described above is first applied to find the optimal design parameters where the PEC patch ($R = 0\Omega$) is restricted to the top of the eRAM ($T_1 = T$), as was done in [3]. The same lossy eRAM material as in [3] (with a dielectric constant of approximately 5-j1.6) is used for the coating material. Fig. 2 shows a representative optimized design (marked as Design P in Fig. 3) and its spectral absorption performance for $\theta = 30^\circ$. There are two dips in the absorption curve for each polarization (located at 7.5 and 10.5 GHz for V and at 7.5 and 12.5 GHz for H). These are caused by, respectively, the patch absorption resonance (due to energy trapped beneath the patch) and the standard front-back destructive interference of the exposed dielectric slab. These two mechanisms are illustrated in the inset of Fig. 2. The overall converged Pareto front with the above design constraints is shown in Fig. 3 as “×.” It is noted that rank-one solutions...
can achieve an average power reflection coefficient down to −7.9 dB at \( T = 3.52 \text{ mm} \). For comparison, the Pareto front for dual-layer absorbers with no patch is also generated via the Pareto GA and plotted as “□” in Fig. 3. These dual-layer designs consist of wax (with a dielectric constant of about 2.4-j0.08) over eRAM. Clearly, the single-layer eRAM with patches is thinner and has superior absorption performance than the reference dual-layer design.

To further improve on the absorption performance, the design is next allowed two additional degrees of freedom: (1) placement of the patch inside the absorber \( (T_1 \leq T) \), and (2) variable patch resistivity \( (0 \leq R \leq 1.200 \Omega) \). The new design freedom resulted in a further improved Pareto front shown as dots in Fig. 3. The average power reflection coefficient can be decreased to −11.26 dB at \( T = 4.84 \text{ mm} \). It is interesting to note that no noticeable performance improvement is achieved initially for thickness \( T < 1.4 \text{ mm} \). However, significant improvements can be obtained when the thickness is increased beyond this point due to the additional design freedoms (details will be discussed later).

For comparison, the Pareto front of an optimized dual-layer design of wax-covered magRAM is also generated and plotted as “△” in Fig. 3. These dual-layer designs consist of wax (with a dielectric constant of 3.2) over ground-plane and the dual-layer magRAM absorber. The weight penalty of the magRAM absorber is also generated and plotted as “×” in Fig. 3. For comparison, the Pareto front of an optimized dual-layer design of magRAM absorber is generated via the Pareto GA and plotted as “○” in Fig. 3. These dual-layer designs consist of wax (with a dielectric constant of 2.4) over ground-plane and the dual-layer magRAM absorber. The weight penalty of the magRAM absorber is nearly approach that of the reference dual-layer design.

It is important to note that, with sufficient thickness, the performance of the single-layer eRAM with patches can nearly approach that of the dual-layer magRAM absorber. The weight penalty of the magRAM and the material bonding issue associated with any dual-layer structure makes the eRAM with patches a potential alternative.

Next, let us examine the absorption physics of the optimized eRAM absorber with patches. The detailed design parameters are plotted in Fig. 4 for the optimized absorber configurations. The patch size \( (W) \) and period \( (P) \) are plotted versus absorber thickness \( (T) \) in Fig. 4(a); and Fig. 4(b) shows the patch height \( (T_1) \) over ground-plane and the patch resistivity \( (R) \) versus absorber thickness. A sudden change in the patch size and period is clearly observed in Fig. 4(a) at the absorber thickness of 3.2 mm. From Fig. 4(b), we also observe that the optimal patch position moves from the top of the absorber to inside the absorber when the absorber thickness exceeds 3.8 mm. Therefore, three distinct classes of optimized designs for \( T \leq 3.2 \text{ mm} \), \( 3.2 \text{ mm} < T < 3.8 \text{ mm} \) and \( T \geq 3.8 \text{ mm} \) are noted. To examine the operating physics of the designs in more detail, three specific optimized designs (labeled as A, B and C) are selected for discussion. For design A \( (T = T_1 = 2.81 \text{ mm}, P = 4.41 \text{ mm}, W = 3.86 \text{ mm}, R = 114 \Omega) \), the resistive patches are located on top of the coating, and the gaps between the patches are physically small \( (P-W = 0.55 \text{ mm}) \). In this case, the patch resistance produces good absorbing characteristics. This effect occurs when the patch size is on the order of half a wavelength in the material. The patch resonance is affected more by its own resistivity than its height within the substrate. The larger the patch height, the broader the resonance dip and the lower the resonant frequency due to fringing effects of the resonant field. For design B \( (T = T_1 = 3.39 \text{ mm}, P = 10.77 \text{ mm}, W = 6.73 \text{ mm}, R = 114 \Omega) \), the patch is still located on top of the coating. Both the patch size and the patch period increase significantly as compared to design A. In this case, the patch resonance is lowered compared to design A due the much larger patch size. However, since there is now a larger gap between neighboring patches \( (P-W = 4.04 \text{ mm}) \), an additional destructive interference dip due to the exposed ground-plane backed dielectric is created. This situation is similar to what was shown in Fig. 2 for design P. For design C \( (T = 4.22 \text{ mm}, T_1 = 1.25 \text{ mm}, P = 10.42 \text{ mm}, W = 6.51 \text{ mm}, R = 19 \Omega) \), the patch is embedded inside the eRAM slab. Fig. 5 shows the spectral absorption performance for \( \theta = 30^\circ \) of this design. Interestingly, this design achieves the desirable broadband response over the frequency range of interest by being able to have three separate resonances. First, the patch resonance...
occurs at a frequency around 8 GHz. Second, the exposed gaps between the patches create a conventional planar absorber that produces a resonance at 11 GHz. Third, the patches themselves serve as an additional ground plane to create a thinner planar absorber to enhance performance above 11 GHz. The three mechanisms are illustrated in the inset of Fig. 5 and labeled as (i), (ii), and (iii). These effects combine to allow eRAM with periodic resistive patches to exhibit absorbing characteristics comparable to those of a dual-layer magRAM.

IV. CONCLUSION

A Pareto genetic algorithm has been applied to design planar absorbers with periodic resistive patches in terms of absorption performance and absorber thickness. The performance of a single-layer eRAM absorber incorporating a resistive patch array can be made comparable to that of a dual-layer magRAM. Three specific designs were selected from the Pareto front to illustrate the different optimization regimes and to investigate the operating principles of each. The best broadband absorbing characteristics are achieved by strong resonance of patches placed near ground as well as by the destructive interference phenomena occurring in the coated patch array and the coated ground-plane.

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Fig. 5. Absorption performance of design C with embedded resistive patches at \( \theta = 30^\circ \). Vertical polarization ( ), Horizontal polarization ( ).